

Search Notes

Application/Control No.

10/725,378

Examiner

Peter Coughlan

Applicant(s)/Patent under
Reexamination

FAN ET AL.

Art Unit

2129

SEARCHED

Class	Subclass	Date	Examiner
706	1	8/23/2006	PDC
706	15	8/23/2006	PDC
706	45	8/23/2006	PDC
700	1	8/23/2006	PDC
700	90	8/23/2006	PDC
704	270	8/23/2006	PDC
706	12	8/23/2006	PDC
705	400	8/23/2006	PDC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East-inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, fan wei	8/23/2006	PDC
East--II--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	8/23/2006	PDC
IEEE--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	8/23/2006	PDC
IEEE--II--nductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, fan wei	8/23/2006	PDC
Google-inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, fan wei	8/23/2006	PDC
Dogpile--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	8/23/2006	PDC
Inventors--Wang Haixun, Yu Philip S, Fan Wei	8/23/2006	PDC